

INFORMATION DISCLOSURE CITATION  
(Use several sheets if necessary)P E  
MAY 18 2004  
CIO  
PATENT & TRADEMARK OFFICE

ATTY DOCKET NO. MIT-114J	SERIAL NO. 09/898,815
Applicant(s) Shi-Chang Wooh	
FILING Date July 5, 2001	GROUP 2878

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SY	6,253,618	07/03/2001	Wooh			
SY	6,092,420	07/25/2000	Kimura et al.			
SY	6,078,788	06/20/2000	Haardt			
SY	6,061,553	05/09/2000	Matsuoka et al.			
SY	5,930,293	07/27/1999	Light et al.			
SY	5,926,503	07/20/1999	Kelton et al.			
SY	5,827,188	10/27/1998	Wright et al.			
SY	5,824,908	10/20/1998	Schindel et al.			
SY	5,818,592	10/06/1998	Womack et al.			
SY	5,814,732	09/29/1998	Nogami			
SY	5,814,730	09/29/1998	Brodeur et al.			

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
SY	JP-4-64350	02/28/1992	Japan			✓	
SY	EP 0 935 258 A1	08/11/1999	Europe				
SY	GB 2008756 A	06/06/1979	United Kingdom				
SY	WO 96/22527	07/25/1996	WIPO				
SY	WO 96/12951	05/02/1996	WIPO				

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

SY		Thompson et al., "Quantitative Nondestructive Evaluation", Center for NDE and Department of Aerospace Engineering and Engineering Mechanics, Iowa State University, American Institute of Physics, Melville, NY, AIP Conference Proceedings, Vol. 19A, pp. 831-838, July (1999).
SY		C.B. Scruby and L.E.Drain, "Laser Ultrasonics: Techniques and Applications", Adam Hilger, Briston UK (1990), Ch. 6, pp. 324-405.

EXAMINER

*[Signature]*

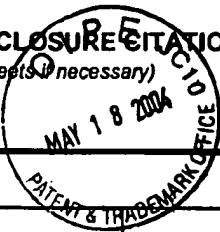
DATE CONSIDERED

7/23/04

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

## INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

ATTY DOCKET NO.  
MIT-114JSERIAL NO.  
09/898,815

Applicant(s) Shi-Chang Wooh

FILING GROUP

Date July 5, 2001

2878

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SY	5,808,199	09/15/1998	Kazys et al.			
SY	5,804,727	09/08/1998	Lu et al.			
SY	5,767,410	06/16/1998	Lareau et al.			
SY	5,763,785	06/09/1998	Chiang			
SY	5,760,307	06/02/1998	Latimer et al.			
SY	5,724,138	03/03/1998	Reich et al.			
SY	5,672,830	09/30/1997	Rogers et al.			
SY	5,671,154	09/23/1997	Iizuka et al.			
SY	5,665,907	09/09/1997	Sheen et al.			
SY	5,650,852	07/22/1997	Chastain et al.			
SY	5,646,350	07/08/1997	Robinson et al.			

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES
SY	GB 2164220 A	03/12/1986	United Kingdom			

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

SY		Safaeinili et al., "Air-Coupled Ultrasonic Estimation of Viscoelastic Stiffnesses in Plates", IEEE Transactions on Ultrasonics, Ferroelectrics, and Frequency Control, Vol 43, pp. 1171-1179 (Nov. 1996).
SY		G.A. Alers, "Railroad Rail Flaw Detection System Based on Electromagnetic Acoustic Transducers", U.S. Department of Transportation Report DOT/FRA/ORD-88/09 (September, 1988).

EXAMINER

DATE CONSIDERED

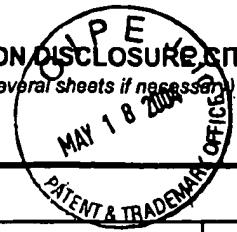
7/23/04

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<b>INFORMATION DISCLOSURE CITATION</b> <small>(Use several sheets if necessary)</small>				ATTY DOCKET NO. MIT-114J		SERIAL NO. 09/898,815	
				<b>Applicant(s)</b> Shi-Chang Wooh <b>FILING Date</b> July 5, 2001 <b>GROUP</b> 2878			
				<b>U.S. PATENT DOCUMENTS</b>			
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
SY	5,629,485	05/13/1997	Rose et al.				
SY	5,627,508	05/06/1997	Cooper et al.				
SY	5,606,256	02/25/1997	Takei				
SY	5,578,758	11/26/1996	Havira et al.				
SY	5,574,989	11/12/1996	Watson et al.				
SY	5,574,224	11/12/1996	Jaeggi				
SY	5,532,697	07/02/1996	Hidaka et al.				
SY	5,522,265	06/04/1996	Jaeggi				
SY	5,488,737	01/30/1996	Harbin et al.				
SY	5,439,157	08/08/1995	Geier et al.				
SY	5,438,872	08/08/1995	Kobayashi et al.				
<b>FOREIGN PATENT DOCUMENTS</b>							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
SY			Wooh et al., Time Frequency Analysis of Broadband Dispersive Waves Using the Wavelet Transform, Review of Progress in Quantitative Nondestructive Evaluations, American Institute of Physics, Melville, NY, AIP Conference Proceedings, Vol. 19A, pp. 831-838, July 25-30, 1999.				
<b>EXAMINER</b> <i>[Signature]</i>				<b>DATE CONSIDERED</b> <i>7/23/04</i>			
<b>*EXAMINER:</b> Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

## INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)



ATTY DOCKET NO.

MIT-114J

SERIAL NO.

09/898,815

Applicant(s) Shi-Chang Wooh

FILING

Date July 5, 2001

GROUP

2878

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SY	5,419,196	05/30/1995	Havira et al.			
SY	5,386,727	02/07/1995	Searle			
SY	5,341,683	08/30/1994	Searle			
SY	5,303,240	04/12/1994	Borras et al.			
SY	5,265,831	11/30/1993	Muller			
SY	5,212,988	05/25/1993	White et al.			
SY	5,172,343	12/15/1992	O'Donnell			
SY	5,154,081	10/13/1992	Thompson et al.			
SY	5,152,010	09/29/1992	Talwar			
SY	5,129,262	07/14/1992	White et al.			
SY	5,125,108	06/23/1992	Talwar			

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER

DATE CONSIDERED

7/23/04

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<b>INFORMATION DISCLOSURE CITATION</b> <small>(Use several sheets if necessary)</small>				ATTY DOCKET NO. MIT-114J		SERIAL NO. 09/898,815	
				Applicant(s) <b>Shi-Chang Wooh</b>		FILING Date <b>July 5, 2001</b> GROUP <b>2878</b>	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
SY	5,035,144	07/30/1991	Aussel				
SY	4,932,618	06/12/1990	Davenport et al.				
SY	4,866,614	09/12/1989	Tam				
SY	4,834,111	05/30/1989	Khanna et al.				
SY	4,821,575	04/18/1989	Fujikake et al.				
SY	4,785,667	11/22/1988	Miyajima et al.				
SY	4,700,574	10/20/1987	Turbe				
SY	4,688,429	08/25/1987	Holroyd				
SY	4,659,224	04/21/1987	Monchalin				
SY	4,633,715	01/06/1987	Monchalin				
SY	4,619,529	10/28/1986	Iuchi et al.				
<b>FOREIGN PATENT DOCUMENTS</b>							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
EXAMINER				DATE CONSIDERED 7/23/04			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

## INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

MAY 18 2004

PATENT &amp; TRADEMARK OFFICE

ATTY DOCKET NO.

MIT-114J

SERIAL NO.

09/898,815

Applicant(s) Shi-Chang Wooh

FILING

Date July 5, 2001

GROUP

2878

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SY	4,570,487	02/18/1986	Gruber			
SY	4,497,210	02/05/1985	Uchida et al.			
SY	4,487,071	12/11/1984	Pagano et al.			
SY	4,481,822	11/13/1984	Kubota et al.			
SY	4,437,031	03/13/1984	Gunshor et al.			
SY	4,372,163	02/08/1983	Tittmann et al.			
SY	4,354,388	10/19/1982	Diepers et al.			
SY	4,248,092	02/03/1981	Vasile et al.			
SY	4,174,636	11/20/1979	Pagano			
SY	4,143,553	03/13/1979	Martens et al.			
SY	4,127,035	11/28/1978	Vasile			

## FOREIGN PATENT DOCUMENTS

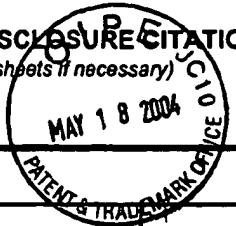
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER	DATE CONSIDERED
	7/23/04

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE CITATION  
(Use several sheets if necessary)



ATTY DOCKET NO.  
MIT-114J

SERIAL NO.  
09/898,815

Applicant(s) Shi-Chang Wooh

FILING Date July 5, 2001

GROUP 2878

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SY	4,004,455	01/25/1977	McKee et al.			
SY	3,962,908	06/15/1976	Joy			
SY	3,937,068	02/10/1976	Joy			
SY	3,812,708	05/28/1974	Cowan et al.			
SY	3,564,488	02/16/1971	Higashi et al.			
SY	US 2001/0020390	09/13/2001	Wooh			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER				DATE CONSIDERED	7/23/04

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>		Docket Number (Optional) MIT-114J	Application Number 09/898,815
		Applicant(s) Shi-Chang Wook	
		Filing Date July 5, 2001	Cross Ref Unit 2878
		OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>	
SV	C.B.Scruby and L.E. Drain, "Laser-Ultrasonics: Techniques and Applications", Adam Hilger, Briston UK (1990), Ch. 6, pp-324-405.		
EXAMINER <i>[Signature]</i>	DATE CONSIDERED 7/23/04		

*[Signature]*  
\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.